WHAT IS CLAIMED IS:

1. A system for testing a device, comprising:

a processor operable to:

execute a plurality of test instructions, the plurality of test instructions operable to test a device; and

generate a plurality of test signals associated with the plurality of test instructions; and

an interface apparatus coupled to the processor and operable to communicate the plurality of test signals to the device, the interface apparatus comprising a plurality of connectors, each connector operable to communicate at least one signal of the plurality of test signals.

2. The system of Claim 1, wherein the plurality of test signals comprises a radio frequency signal and a high speed digital signal.

3. The system of Claim 1, wherein:

the plurality of test signals comprises a radio frequency signal and a high speed digital signal; and

the plurality of connectors comprises a first connector operable to communicate the radio frequency signal and a second connector operable to communicate the high speed digital signal.

4. The system of Claim 1, wherein the interface apparatus comprises a coupling plane, the coupling plane comprising the plurality of connectors arranged in a plurality of rows.

5. The system of Claim 1, wherein:

the interface apparatus has an annular shape with an inner edge and an outer edge; and

a portion of the plurality of connectors is arranged in a curved line between the inner edge and the outer edge.

6. The system of Claim 1, wherein the processor is located at a test assembly comprising a movable rack, the movable rack operable to transport the test assembly from a first location to a second location.

7. The system of Claim 1, wherein the processor is located at a test assembly comprising a movable rack, the movable rack operable to move the test assembly from a first height to a second height.

8. The system of Claim 1, further comprising a test head coupled to the interface apparatus and operable to apply the plurality of test signals to the device.

9. The system of Claim 1, further comprising a plurality of test modules coupled to the processor, the plurality of test modules operable to transmit the plurality of test signals to the interface apparatus.

10. The system of Claim 1, further comprising a handler coupled to the interface apparatus and operable to automatically position the device substantially proximate to the interface apparatus.

11. An interface apparatus for communicating a plurality of signals, comprising:

a plurality of first connectors, each first connector operable to communicate a test signal comprising a radio frequency signal generated by a processor; and

a plurality of second connectors operable to communicate a test signal comprising a high speed data signal generated by a processor.

12. The interface apparatus of Claim 11, further comprising a coupling plane, the coupling plane comprising the plurality of first connectors and the plurality of second connectors arranged in a plurality of rows.

13. The interface apparatus of Claim 11, wherein:

the interface apparatus has an annular shape with an inner edge and an outer edge; and

a portion of the plurality of connectors is arranged in a curved line between the inner edge and the outer edge.

14. A method for testing a device, comprising:

executing a plurality of test instructions, the plurality of test instructions operable to test a device;

generating a plurality of test signals associated with the plurality of test instructions; and

communicating the plurality of test signals to the device using an interface apparatus, the interface apparatus comprising a plurality of connectors, each connector operable to communicate at least one signal of the plurality of test signals.

15. The method of Claim 14, wherein the plurality of test signals comprises a radio frequency signal and a high speed digital signal.

16. The method of Claim 14, wherein the plurality of test signals comprises a radio frequency signal and a high speed digital signal, and further comprising:

communicating the radio frequency signal at a first connector of the plurality of connectors; and

communicating the high speed digital signal at a second connector of the plurality of connectors.

17. The method of Claim 14, wherein the interface apparatus comprises a coupling plane, the coupling plane comprising the plurality of connectors arranged in a plurality of rows.

18. The method of Claim 14, wherein:

the interface apparatus has an annular shape with an inner edge and an outer edge; and

a portion of the plurality of connectors is arranged in a curved line between the inner edge and the outer edge.

19. A system for testing a device, comprising:

means for executing a plurality of test instructions, the plurality of test instructions operable to test a device;

means for generating a plurality of test signals associated with the plurality of test instructions; and

means for communicating the plurality of test signals to the device, the means for communicating comprising a plurality of connectors, each connector operable to communicate at least one signal of the plurality of test signals.

20. A system for testing a device, comprising:

a processor operable to:

execute a plurality of test instructions, the plurality of test instructions operable to test a device; and

generate a plurality of test signals associated with the plurality of test instructions, the plurality of test signals comprising a radio frequency signal and a high speed digital signal, the processor located at a test assembly comprising a movable rack, the movable rack operable to:

transport the test assembly from a first location to a second location; and

move the test assembly from a first height to a second height;

an interface apparatus coupled to the processor and operable to communicate the plurality of test signals to the device, the interface apparatus comprising a coupling plane, the coupling plane comprising a plurality of connectors arranged in a plurality of rows, the interface apparatus having an annular shape with an inner edge and an outer edge, a portion of the plurality of connectors arranged in a curved line between the inner edge and the outer edge, each connector of the plurality of connectors operable to communicate at least one signal of the plurality of test signals, the plurality of connectors comprising a first connector operable to communicate the radio frequency signal and a second connector operable to communicate the high speed digital signal;

a plurality of test modules coupled to the processor, the plurality of test modules operable to

transmit the plurality of test signals to the interface apparatus;

a test head coupled to the interface apparatus and operable to apply the plurality of test signals to the device; and

a handler coupled to the interface apparatus and operable to automatically position the device substantially proximate to the interface apparatus.